











AM26C31

SLLS103O - DECEMBER 1990 - REVISED JUNE 2016

AM26C31 Quadruple Differential Line Driver

Features

- Meets or Exceeds the Requirements of TIA/EIA-422-B and ITU Recommendation V.11
- Low Power, $I_{CC} = 100 \mu A$ Typical
- Operates From a Single 5-V Supply
- High Speed, $t_{PLH} = t_{PHL} = 7$ ns Typical
- Low Pulse Distortion, $t_{sk(p)} = 0.5$ ns Typical
- High Output Impedance in Power-Off Conditions
- Improved Replacement for AM26LS31 Device
- Available in Q-Temp Automotive
 - High-Reliability Automotive Applications
 - Configuration Control and Print Support
 - Qualification to Automotive Standards
- On Products Compliant to MIL-PRF-38535. All Parameters Are Tested Unless Otherwise Noted. On All Other Products, Production Processing Does Not Necessarily Include Testing of All Parameters.

2 Applications

- Chemical and Gas Sensors
- Field Transmitters: Temperature Sensors and Pressure Sensors
- Military: Radars and Sonars
- Motor Control: Brushless DC and Brushed DC
- Military and Avionics Imaging
- Temperature Sensors and Controllers Using Modbus

3 Description

The AM26C31 device is a differential line driver with complementary outputs, designed to meet the requirements of TIA/EIA-422-B and ITU (formerly CCITT). The 3-state outputs have high-current capability for driving balanced lines, such as twistedpair or parallel-wire transmission lines, and they provide the high-impedance state in the power-off condition. The enable functions are common to all four drivers and offer the choice of an active-high (G) or active-low (G) enable input. BiCMOS circuitry reduces power consumption without sacrificing speed.

The AM26C31C device is characterized for operation from 0°C to 70°C, the AM26C31I device is characterized for operation from -40°C to 85°C, the AM26C31Q device is characterized for operation over the automotive temperature range of -40°C to 125°C, and the AM26C31M device is characterized for operation over the full military temperature range of -55°C to 125°C.

Device Information⁽¹⁾

PART NUMBER	PACKAGE	BODY SIZE (NOM)
AM26C31J	CDIP (16)	19.56 mm × 6.92 mm
AM26C31N	PDIP (16)	19.30 mm × 6.35 mm
AM26C31NS	SO (16)	10.30 mm × 5.30 mm
AM26C31W	CFP (16)	10.30 mm × 6.73 mm
AM26C31D	SOIC (16)	9.90 mm × 3.91 mm
AM26C31DB	SSOP (16)	6.20 mm × 5.30 mm
AM26C31PW	TSSOP (16)	5.00 mm × 4.40 mm
AM26C31FK	LCCC (20)	8.89 mm × 8.89 mm

(1) For all available packages, see the orderable addendum at the end of the data sheet.

Common Application Diagram

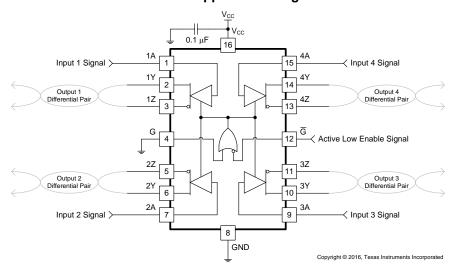




Table of Contents

1	Features 1	8 Detailed Description 10
2	Applications 1	8.1 Overview 10
3	Description 1	8.2 Functional Block Diagrams
4	Revision History2	8.3 Feature Description11
5	Pin Configuration and Functions	8.4 Device Functional Modes11
6	Specifications4	9 Application and Implementation 12
•	6.1 Absolute Maximum Ratings	9.1 Application Information
	6.2 ESD Ratings	9.2 Typical Application12
	6.3 Recommended Operating Conditions	10 Power Supply Recommendations 13
	6.4 Thermal Information	11 Layout 14
	6.5 Electrical Characteristics: AM26C31C and AM26C31I	11.1 Layout Guidelines 14 11.2 Layout Example14
	6.6 Electrical Characteristics: AM26C31Q and AM26C31M	12 Device and Documentation Support 15
	6.7 Switching Characteristics: AM26C31C and AM26C31L	12.1 Receiving Notification of Documentation Updates 15 12.2 Community Resources
	6.8 Switching Characteristics: AM26C31Q and AM26C31M	12.3 Trademarks
	6.9 Typical Characteristics	12.5 Glossary 15
7	Parameter Measurement Information 8	13 Mechanical, Packaging, and Orderable Information15

4 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

Changes from Revision N (October 2011) to Revision O

Page

•	Updated the Features section and added the Applications section, the Device Information table, ESD Ratings table,	
	Feature Description section, Device Functional Modes, Application and Implementation section, Power Supply	
	Recommendations section, Layout section, Device and Documentation Support section, and Mechanical,	
	Packaging, and Orderable Information section.	1
•	Deleted Ordering Information table, see POA at the end of the data sheet	1
•	Changed Thermal Information table	5

Changes from Revision M (June 2008) to Revision N

Page

Changed units to mA from µA to fix units typo.

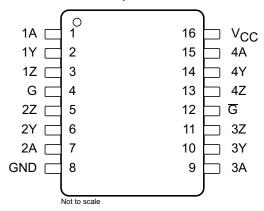
Submit Documentation Feedback

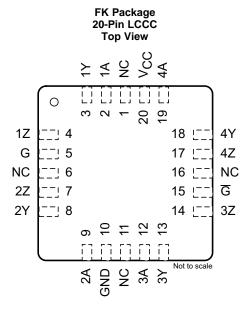
Copyright © 1990–2016, Texas Instruments Incorporated



5 Pin Configuration and Functions

J, W, D, DB, NS, N, or PW Package 16-Pin CDIP, CFP, SOIC, SSOP, SO, PDIP, or TSSOP Top View





Pin Functions

	PIN					
NAME	CDIP, CFP, SOIC, SSOP, SO, PDIP, TSSOP	LCCC	I/O	DESCRIPTION		
1A	1	2	I	Driver 1 input		
1Y	2	3	0	Driver 1 output		
1Z	3	4	0	Driver 1 inverted output		
2A	7	9	_	Driver 2 input		
2Y	6	8	0	Driver 2 output		
2Z	5	7	0	Driver 2 inverted output		
3A	9	12	I	Driver 3 input		
3Y	10	13	0	Driver 3 output		
3Z	11	14	0	Driver 3 inverted output		
4A	15	19	I	Driver 3 input		
4Y	14	18	0	Driver 3 output		
4Z	13	17	0	Driver 3 inverted output		
G	4	5	I	Active high enable		
G	12	15	I	Active low enable		
GND	8	10		Ground pin		
NC ⁽¹⁾	_	1, 6, 11, 16	_	No internal connection		
V _{CC}	16	20	_	Power pin		

(1) NC - No connection



6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)⁽¹⁾

		MIN	MAX	UNIT
V _{CC}	Supply voltage (2)	-0.5	7	V
V_{I}	Input voltage	-0.5	$V_{CC} + 0.5$	V
V_{ID}	Differential input voltage	-14	14	V
Vo	Output voltage	-0.5	7	
I _{IK} I _{OK}	Input or output clamp current		±20	mA
Io	Output current		±150	mA
	V _{CC} current		200	mA
	GND current	-200		mA
TJ	Operating virtual junction temperature		150	°C
T _{stg}	Storage temperature	-65	150	°C

⁽¹⁾ Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

6.2 ESD Ratings

			VALUE	UNIT
V		Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001 (1)	±2000	V
V _(ESD)	discharge	Charged-device model (CDM), per JEDEC specification JESD22-C101 (2)	±1000	V

⁽¹⁾ JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

6.3 Recommended Operating Conditions

			MIN	NOM	MAX	UNIT
V _{CC}	Supply voltage		4.5	5	5.5	V
V_{ID}	Differential input voltage			±7		V
V_{IH}	High-level input voltage		2			V
V_{IL}	Low-level input voltage				8.0	V
I _{OH}	High-level output current				-20	mA
I _{OL}	Low-level output current				20	mA
		AM26C31C	0		70	
_	Operating free air temperature	AM26C31I	-40		85	°C
T _A	Γ _A Operating free-air temperature	AM26C31Q	-40		125	
	AM26C31M		-55		125	

⁽²⁾ All voltage values, except differential voltages, are with respect to the network ground terminal.

⁽²⁾ JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.



6.4 Thermal Information

					AM260	C31				
тн	THERMAL METRIC ⁽¹⁾		DB (SSOP)	PW (TSSOP)	NS (SO)	N (PDIP)	J (CDIP)	W (CFP)	FK (LCCC)	UNIT
		16 PINS	16 PINS	16 PINS	16 PINS	16 PINS	16 PINS	16 PINS	16 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance (2)(3)	75.3	93.1	102.1	75.6	44.5	_	_	_	°C/W
$R_{\theta JC(top)}$	Junction-to-case (top) thermal resistance	35.6	43.8	37.2	32.6	31.1	39.3 ⁽⁴⁾	58.9 ⁽⁴⁾	37.1 ⁽⁴⁾	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	32.5	43.6	47.0	36.4	24.5	56.4 ⁽⁴⁾	109.3(4)	36.2 ⁽⁴⁾	°C/W
ΨЈТ	Junction-to-top characterization parameter	7.1	9.6	2.8	5.7	15.4	_	_	_	°C/W
ΨЈВ	Junction-to-board characterization parameter	32.3	43.1	46.4	36.0	24.4	_	_	_	°C/W
$R_{\theta JC(bot)}$	Junction-to-case (bottom) thermal resistance	n/a	n/a	n/a	n/a	n/a	12.0 ⁽⁴⁾	5.7 ⁽⁴⁾	4.3 ⁽⁴⁾	°C/W

- (1) For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.
- (2) Maximum power dissipation is a function of $T_{J(max)}$, $R_{\theta JA}$, and T_A . The maximum allowable power dissipation at any allowable ambient temperature is $P_D = (T_{J(max)} T_A) / R_{\theta JA}$. Operating at the absolute maximum T_J of 150°C can affect reliability.
- (3) The package thermal impedance is calculated in accordance with JESD 51-7.
- (4) Modelling assumption: MIL-STD-883 for $R_{\theta JC(top)}$ and $R_{\theta JC(bot)}$ JESD51 for $R_{\theta JB}$.

6.5 Electrical Characteristics: AM26C31C and AM26C31I

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

	PARAMETER	TES	ST CONDITIONS	MIN	TYP ⁽¹⁾	MAX	UNIT
V _{OH}	High-level output voltage	$I_0 = -20 \text{ m}$	A	2.4	3.4		V
V _{OL}	Low-level output voltage	I _O = 20 mA			0.2	0.4	V
V _{OD}	Differential output voltage magnitude	$R_L = 100 \Omega$, see Figure 2	2	3.1		V
$\Delta V_{OD} $	Change in magnitude of differential output voltage (2)	R _L = 100 Ω	, see Figure 2			±0.4	V
V _{OC}	Common-mode output voltage	$R_L = 100 \Omega$, see Figure 2			3	V
$\Delta V_{OC} $	Change in magnitude of common-mode output voltage ⁽²⁾	$R_L = 100 \Omega$, see Figure 2			±0.4	V
I	Input current	$V_I = V_{CC}$ or	GND			±1	μΑ
	Daire and the state of the stat	V 0	V _O = 6 V			100	^
I _{O(off)}	Driver output current with power off	$V_{CC} = 0$	V _O = -0.25 V			-100	μΑ
Ios	Driver output short-circuit current	V _O = 0		-30		-150	mA
	LPak Samada a a Watata a day ta a ana at	V _O = 2.5 V				20	•
loz	High-impedance off-state output current	V _O = 0.5 V				-20	μΑ
	Orizonal samula samul		V _I = 0 or 5 V			100	μΑ
Icc	Quiescent supply current	$I_{O} = 0$	$V_I = 2.4 \text{ V or } 0.5 \text{ V}^{(3)}$		1.5	3	mA
C _i	Input capacitance				6		pF

- (1) All typical values are at $V_{CC} = 5 \text{ V}$ and $T_A = 25^{\circ}\text{C}$.
- (2) ∆|V_{OD}| and ∆|V_{OC}| are the changes in magnitude of V_{OD} and V_{OC}, respectively, that occur when the input is changed from a high level to a low level.

(3) This parameter is measured per input. All other inputs are at 0 or 5 V.



6.6 Electrical Characteristics: AM26C31Q and AM26C31M

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

	PARAMETER	TES	T CONDITIONS	MIN	TYP ⁽¹⁾	MAX	UNIT
V _{OH}	High-level output voltage	$I_0 = -20 \text{ m/s}$	Ą	2.2	3.4		V
V _{OL}	Low-level output voltage	I _O = 20 mA			0.2	0.4	V
V _{OD}	Differential output voltage magnitude	$R_L = 100 \Omega$, see Figure 2	2	3.1		V
$\Delta V_{OD} $	Change in magnitude of differential output voltage ⁽²⁾	$R_L = 100 \Omega$, see Figure 2			±0.4	V
V _{oc}	Common-mode output voltage	$R_L = 100 \Omega$, see Figure 2			3	V
Δ V _{OC}	Change in magnitude of common-mode output voltage (2)	$R_L = 100 \Omega$, see Figure 2			±0.4	V
I _I	Input current	$V_I = V_{CC}$ or	GND	±1		μА	
	Driver and advantage of the second of	., .	V _O = 6 V			100	^
I _{O(off)}	Driver output current with power off	er output current with power off $V_{CC} = 0$ $V_{OC} = 0$				-100	μΑ
Ios	Driver output short-circuit current	$V_O = 0$				-170	mA
	High importance off state output suggest	V _O = 2.5 V				20	۸
loz	High-impedance off-state output current	V _O = 0.5 V		-20		μΑ	
	Oriental amelia amelia		V _I = 0 or 5 V			100	μА
I _{CC}	Quiescent supply current	$I_{O} = 0$	$V_1 = 2.4 \text{ V or } 0.5 \text{ V}^{(3)}$			3.2	mA
Ci	Input capacitance				6		pF

6.7 Switching Characteristics: AM26C31C and AM26C31I

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP ⁽¹⁾	MAX	UNIT
t _{PLH}	Propagation delay time, low-to-high-level output	C4 is ones and Figure 2	3	7	12	
t _{PHL}	Propagation delay time, high-to-low-level output	S1 is open, see Figure 3	3	7	12	ns
t _{sk(p)}	Pulse skew time (t _{PLH} - t _{PHL})	S1 is open, see Figure 3		0.5	4	ns
$t_{r(OD)}, t_{f(OD)}$	Differential output rise and fall times	S1 is open, see Figure 4		5	10	ns
t _{PZH}	Output enable time to high level	C1 is alonged one Figure F		10	19	
t _{PZL}	Output enable time to low level	S1 is closed, see Figure 5		10	19	ns
t _{PHZ}	Output disable time from high level	C1 is alonged one Figure F		7	16	
t_{PLZ}	Output disable time from low level	S1 is closed, see Figure 5		7	16	ns
C_{pd}	Power dissipation capacitance (each driver) ⁽²⁾	S1 is open, see Figure 3		170		pF

 ⁽¹⁾ All typical values are at V_{CC} = 5 V and T_A = 25°C.
 (2) Δ|V_{OD}| and Δ|V_{OC}| are the changes in magnitude of V_{OD} and V_{OC}, respectively, that occur when the input is changed from a high level to a low level.

This parameter is measured per input. All other inputs are at 0 or 5 V.

⁽¹⁾ All typical values are at V_{CC} = 5 V and T_A = 25°C. (2) C_{pd} is used to estimate the switching losses according to P_D = C_{pd} × V_{CC} 2 × f, where f is the switching frequency.



6.8 Switching Characteristics: AM26C31Q and AM26C31M

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP ⁽¹⁾	MAX	UNIT
t _{PLH}	Propagation delay time, low-to-high-level output			7	12	20
t _{PHL}	Propagation delay time, high-to-low-level output	S1 is open, see Figure 3		6.5	12	ns
t _{sk(p)}	Pulse skew time (t _{PLH} - t _{PHL})	S1 is open, see Figure 3		0.5	4	ns
$t_{r(OD)}, t_{f(OD)}$	Differential output rise and fall times	S1 is open, see Figure 4		5	12	ns
t _{PZH}	Output enable time to high level	C1 is alread and Figure 5		10	19	
t _{PZL}	Output enable time to low level	S1 is closed, see Figure 5		10	19	ns
t _{PHZ}	Output disable time from high level	C1 is alread and Figure 5		7	16	
t _{PLZ}	Output disable time from low level	S1 is closed, see Figure 5		7	16	ns
C _{pd}	Power dissipation capacitance (each driver) (2)	S1 is open, see Figure 3		100		pF

⁽¹⁾ All typical values are at $V_{CC} = 5 \text{ V}$ and $T_A = 25^{\circ}\text{C}$.

6.9 Typical Characteristics

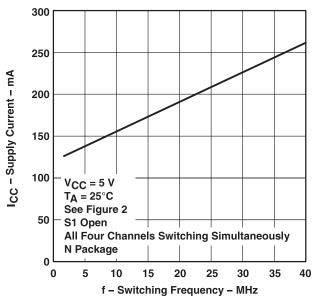


Figure 1. Supply Current vs Switching Frequency

⁽²⁾ C_{pd} is used to estimate the switching losses according to $P_D = C_{pd} \times V_{CC}^2 \times f$, where f is the switching frequency.



7 Parameter Measurement Information

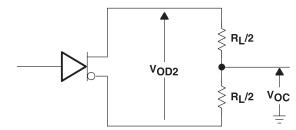
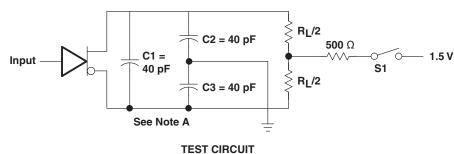


Figure 2. Differential and Common-Mode Output Voltages

- A. C1, C2, and C3 include probe and jig capacitance.
- B. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, duty cycle \leq 50%, and t_r , $t_f \leq$ 6 ns.



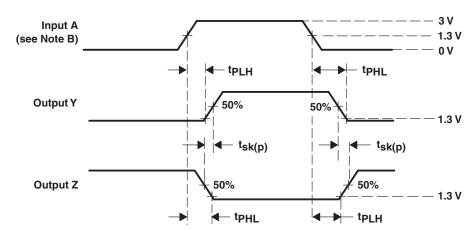


Figure 3. Propagation Delay Time and Skew Waveforms and Test Circuit

- A. C1, C2, and C3 include probe and jig capacitance.
- B. All input pulses are supplied by generators having the following characteristics: PRR ≤ 1 MHz, duty cycle ≤ 50%, and t_r, t_f ≤ 6 ns.



Parameter Measurement Information (continued)

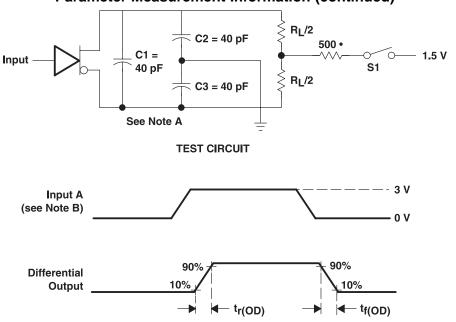
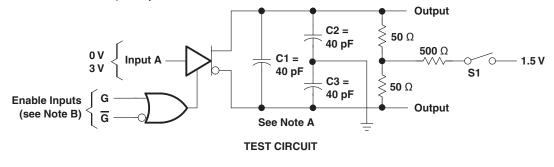


Figure 4. Differential-Output Rise- and Fall-Time Waveforms and Test Circuit

- A. C1, C2, and C3 include probe and jig capacitance.
- All input pulses are supplied by generators having the following characteristics: PRR ≤ 1 MHz, duty cycle ≤ 50%, and $t_r, t_f \le 6 \text{ ns.}$

VOLTAGE WAVEFORMS

Each enable is tested separately.



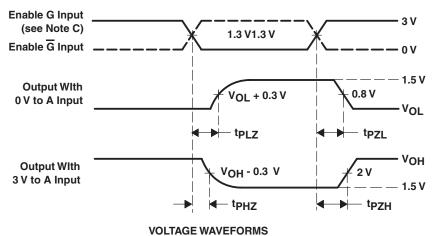


Figure 5. Output Enable and Disable Time Waveforms and Test Circuit

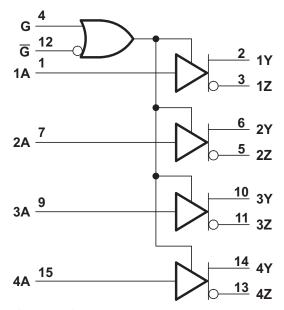


8 Detailed Description

8.1 Overview

The AM26C31 is a quadruple differential line driver with complementary outputs. The device is designed to meet the requirements of TIA/EIA-422-B and ITU (formerly CCITT), and it is generally used to communicate over relatively long wires in noisy environments.

8.2 Functional Block Diagrams



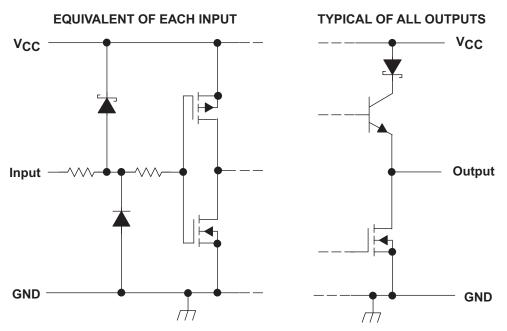
Copyright © 2016, Texas Instruments Incorporated

Pin numbers shown are for the D, DB, J, N, NS, PW, and W packages.

Figure 6. Logic Diagram (Positive Logic)



Functional Block Diagrams (continued)



Copyright © 2016, Texas Instruments Incorporated

Figure 7. Schematics of Inputs and Outputs

8.3 Feature Description

8.3.1 Active-High and Active-Low

The device can be configured using the G and \overline{G} logic inputs to select transmitter output. A logic high on the G pin or a logic low on the \overline{G} pin enables the device to operate. These pins are simply a way to configure the logic to match that of the receiving or transmitting controller or microprocessor.

8.3.2 Operates from a Single 5-V Supply

Both the logic and transmitters operate from a single 5-V rail, making designs much more simple. The line drivers and receivers can operate off the same rail as the host controller or a similar low voltage supply, thus simplifying power structure.

8.4 Device Functional Modes

Table 1 lists the functional modes of the AM26C31.

Table 1. Function Table (Each Driver)(1)

INPUT	ENA	BLES	OUTPUTS			
Α	G	G	Υ	Z		
Н	Н	X	Н	L		
L	Н	X	L	Н		
Н	Χ	L	Н	L		
L	Х	L	L	Н		
Х	L	Н	Z	Z		

(1) H = High level,

L = Low level,

X = Irrelevant,

Z = High impedance (off)



9 Application and Implementation

NOTE

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

9.1 Application Information

When designing a system that uses drivers, receivers, and transceivers that comply with RS-422, proper cable termination is essential for highly reliable applications with reduced reflections in the transmission line. Because RS-422 allows only one driver on the bus, if termination is used, it is placed only at the end of the cable near the last receiver. Factors to consider when determining the type of termination usually are performance requirements of the application and the ever-present factor, cost. The different types of termination techniques discussed are unterminated lines, parallel termination, AC termination, and multipoint termination. For laboratory experiments, 100 feet of 100- Ω , 24-AWG, twisted-pair cable (Bertek) was used. A single driver and receiver, TI AM26C31C and AM26C32C, respectively, were tested at room temperature with a 5-V supply voltage. To show voltage waveforms related to transmission-line reflections, the first plot shows output waveforms from the driver at the start of the cable (A/B); the second plot shows input waveforms to the receiver at the far end of the cable (Y).

9.2 Typical Application

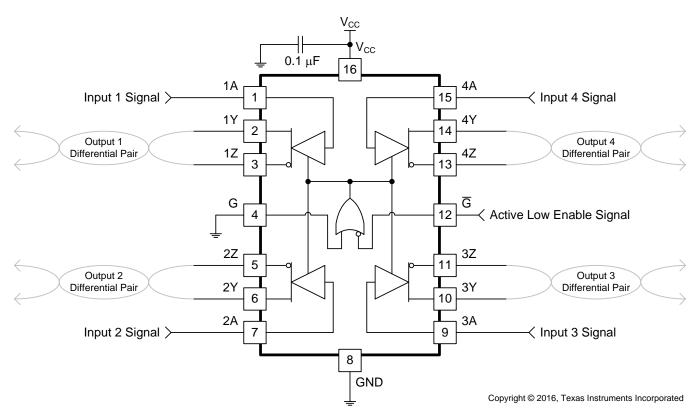


Figure 8. Differential Terminated Configuration With All Channels and Active Low Enable Used

9.2.1 Design Requirements

Resistor and capacitor (if used) termination values are shown for each laboratory experiment, but vary from system to system. For example, the termination resistor, R_T , must be within 20% of the characteristic impedance, Zo, of the cable and can vary from about 80 Ω to 120 Ω .



Typical Application (continued)

9.2.2 Detailed Design Procedure

Ensure values in Absolute Maximum Ratings are not exceeded.

Supply voltage, V_{IH} , and V_{IL} must comply with *Recommended Operating Conditions*.

9.2.3 Application Curve

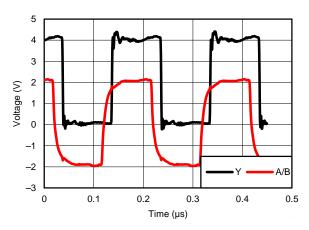


Figure 9. Differential 120- Ω Terminated Output Waveforms (Cat 5E Cable)

10 Power Supply Recommendations

Place 0.1-µF bypass capacitors close to the power-supply pins to reduce errors coupling in from noisy or high impedance power supplies.



11 Layout

11.1 Layout Guidelines

For best operational performance of the device, use good PCB layout practices, including:

- Noise can propagate into analog circuitry through the power pins of the circuit as a whole, as well as the
 operational amplifier. Bypass capacitors are used to reduce the coupled noise by providing low impedance
 power sources local to the analog circuitry.
 - Connect low-ESR, 0.1-µF ceramic bypass capacitors between each supply pin and ground, placed as close to the device as possible. A single bypass capacitor from V+ to ground is applicable for singlesupply applications.
- Separate grounding for analog and digital portions of circuitry is one of the simplest and most effective
 methods of noise suppression. One or more layers on multilayer PCBs are usually devoted to ground planes.
 A ground plane helps distribute heat and reduces EMI noise pickup. Make sure to physically separate digital
 and analog grounds, paying attention to the flow of the ground current.
- To reduce parasitic coupling, run the input traces as far away from the supply or output traces as possible. If
 it is not possible to keep them separate, it is much better to cross the sensitive trace perpendicular as
 opposed to in parallel with the noisy trace.
- Place the external components as close to the device as possible. Keeping RF and RG close to the inverting input minimizes parasitic capacitance.
- Keep the length of input traces as short as possible. Always remember that the input traces are the most sensitive part of the circuit.
- Consider a driven, low-impedance guard ring around the critical traces. A guard ring can significantly reduce leakage currents from nearby traces that are at different potentials.

11.2 Layout Example

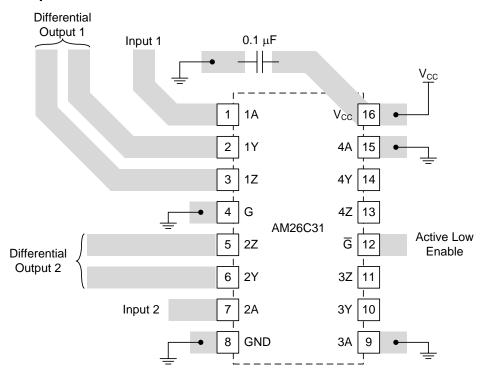


Figure 10. Trace Layout on PCB and Recommendations



12 Device and Documentation Support

12.1 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. In the upper right corner, click on *Alert me* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

12.2 Community Resources

The following links connect to TI community resources. Linked contents are provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

TI E2E™ Online Community TI's Engineer-to-Engineer (E2E) Community. Created to foster collaboration among engineers. At e2e.ti.com, you can ask questions, share knowledge, explore ideas and help solve problems with fellow engineers.

Design Support *TI's Design Support* Quickly find helpful E2E forums along with design support tools and contact information for technical support.

12.3 Trademarks

E2E is a trademark of Texas Instruments.

All other trademarks are the property of their respective owners.

12.4 Electrostatic Discharge Caution



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

12.5 Glossary

SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms, and definitions.

13 Mechanical, Packaging, and Orderable Information

The following pages include mechanical packaging and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser based versions of this data sheet, refer to the left hand navigation.





4-Mar-2016

PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead/Ball Finish (6)	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
5962-9163901M2A	ACTIVE	LCCC	FK	20	1	TBD	POST-PLATE	N / A for Pkg Type	-55 to 125	5962- 9163901M2A AM26C31M	Samples
5962-9163901MEA	ACTIVE	CDIP	J	16	1	TBD	A42	N / A for Pkg Type	-55 to 125	5962-9163901ME A AM26C31M	Samples
5962-9163901MFA	ACTIVE	CFP	W	16	1	TBD	A42	N / A for Pkg Type	-55 to 125	5962-9163901MF A AM26C31M	Samples
5962-9163901Q2A	ACTIVE	LCCC	FK	20	1	TBD	POST-PLATE	N / A for Pkg Type	-55 to 125	5962- 9163901Q2A AM26C31 MFKB	Samples
5962-9163901QEA	ACTIVE	CDIP	J	16	1	TBD	A42	N / A for Pkg Type	-55 to 125	5962-9163901QE A AM26C31MJB	Samples
5962-9163901QFA	ACTIVE	CFP	W	16	1	TBD	A42	N / A for Pkg Type	-55 to 125	5962-9163901QF A AM26C31MWB	Samples
AM26C31CD	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	0 to 70	AM26C31C	Samples
AM26C31CDBLE	OBSOLETE	SSOP	DB	16		TBD	Call TI	Call TI	0 to 70		
AM26C31CDBR	ACTIVE	SSOP	DB	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	0 to 70	26C31	Samples
AM26C31CDBRG4	ACTIVE	SSOP	DB	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	0 to 70	26C31	Samples
AM26C31CDE4	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	0 to 70	AM26C31C	Samples
AM26C31CDG4	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	0 to 70	AM26C31C	Samples
AM26C31CDR	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	0 to 70	AM26C31C	Samples
AM26C31CDRE4	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	0 to 70	AM26C31C	Samples





www.ti.com

4-Mar-2016

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead/Ball Finish (6)	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
AM26C31CDRG4	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	0 to 70	AM26C31C	Samples
AM26C31CN	ACTIVE	PDIP	N	16	25	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	0 to 70	AM26C31CN	Samples
AM26C31CNE4	ACTIVE	PDIP	N	16	25	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	0 to 70	AM26C31CN	Samples
AM26C31CNSR	ACTIVE	SO	NS	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	0 to 70	26C31	Samples
AM26C31CNSRG4	ACTIVE	SO	NS	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	0 to 70	26C31	Samples
AM26C31ID	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	AM26C31I	Samples
AM26C31IDBLE	OBSOLETI	SSOP	DB	16		TBD	Call TI	Call TI	-40 to 85		
AM26C31IDBR	ACTIVE	SSOP	DB	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	26C31I	Samples
AM26C31IDBRE4	ACTIVE	SSOP	DB	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	26C31I	Samples
AM26C31IDBRG4	ACTIVE	SSOP	DB	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	26C31I	Samples
AM26C31IDE4	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	AM26C31I	Samples
AM26C31IDG4	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	AM26C31I	Samples
AM26C31IDR	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU CU SN	Level-1-260C-UNLIM	-40 to 85	AM26C31I	Samples
AM26C31IDRE4	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	AM26C31I	Samples
AM26C31IDRG4	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	AM26C31I	Samples
AM26C31IN	ACTIVE	PDIP	N	16	25	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-40 to 85	AM26C31IN	Samples
AM26C31INE4	ACTIVE	PDIP	N	16	25	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-40 to 85	AM26C31IN	Samples
AM26C31INSR	ACTIVE	SO	NS	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	26C31I	Samples





www.ti.com

4-Mar-2016

Orderable Device	Status	Package Type	Package	Pins	Package	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking	Samples
	(1)		Drawing		Qty	(2)	(6)	(3)		(4/5)	
AM26C31IPW	ACTIVE	TSSOP	PW	16	90	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	26C31I	Samples
AM26C31IPWG4	ACTIVE	TSSOP	PW	16	90	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	26C31I	Samples
AM26C31IPWR	ACTIVE	TSSOP	PW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU CU SN	Level-1-260C-UNLIM	-40 to 85	26C31I	Samples
AM26C31IPWRG4	ACTIVE	TSSOP	PW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	26C31I	Samples
AM26C31MFKB	ACTIVE	LCCC	FK	20	1	TBD	POST-PLATE	N / A for Pkg Type	-55 to 125	5962- 9163901Q2A AM26C31 MFKB	Samples
AM26C31MJB	ACTIVE	CDIP	J	16	1	TBD	A42	N / A for Pkg Type	-55 to 125	5962-9163901QE A AM26C31MJB	Samples
AM26C31MWB	ACTIVE	CFP	W	16	1	TBD	A42	N / A for Pkg Type	-55 to 125	5962-9163901QF A AM26C31MWB	Samples
AM26C31QD	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	AM26C31Q	Samples
AM26C31QDG4	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	26C31Q	Samples
AM26C31QDR	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	AM26C31Q	Samples
AM26C31QDRG4	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	26C31Q	Samples

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

TBD: The Pb-Free/Green conversion plan has not been defined.

⁽²⁾ Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

PACKAGE OPTION ADDENDUM



4-Mar-2016

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes. **Pb-Free** (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead/Ball Finish Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

OTHER QUALIFIED VERSIONS OF AM26C31, AM26C31M:

Catalog: AM26C31

■ Enhanced Product: AM26C31-EP, AM26C31-EP

Military: AM26C31M

NOTE: Qualified Version Definitions:

- Catalog TI's standard catalog product
- Enhanced Product Supports Defense, Aerospace and Medical Applications



PACKAGE OPTION ADDENDUM

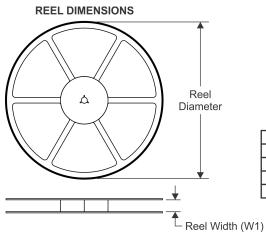
4-Mar-2016

• Military - QML certified for Military and Defense Applications

PACKAGE MATERIALS INFORMATION

www.ti.com 14-Mar-2016

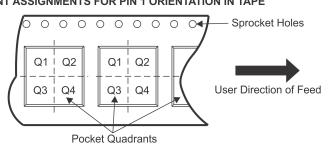
TAPE AND REEL INFORMATION



TAPE DIMENSIONS + K0 - P1 - B0 W Cavity - A0 -

	Dimension designed to accommodate the component width
	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

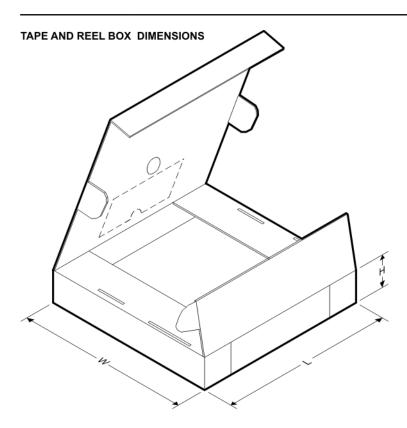


*All dimensions are nominal

All dimensions are nominal												
Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
AM26C31CDBR	SSOP	DB	16	2000	330.0	16.4	8.2	6.6	2.5	12.0	16.0	Q1
AM26C31CDR	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
AM26C31IDBR	SSOP	DB	16	2000	330.0	16.4	8.2	6.6	2.5	12.0	16.0	Q1
AM26C31IDR	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
AM26C31IDR	SOIC	D	16	2500	330.0	16.8	6.5	10.3	2.1	8.0	16.0	Q1
AM26C31IDRG4	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
AM26C31IPWR	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
AM26C31IPWR	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
AM26C31IPWRG4	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
AM26C31QDR	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
AM26C31QDRG4	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1

PACKAGE MATERIALS INFORMATION

www.ti.com 14-Mar-2016



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
AM26C31CDBR	SSOP	DB	16	2000	367.0	367.0	38.0
AM26C31CDR	SOIC	D	16	2500	333.2	345.9	28.6
AM26C31IDBR	SSOP	DB	16	2000	367.0	367.0	38.0
AM26C31IDR	SOIC	D	16	2500	333.2	345.9	28.6
AM26C31IDR	SOIC	D	16	2500	364.0	364.0	27.0
AM26C31IDRG4	SOIC	D	16	2500	333.2	345.9	28.6
AM26C31IPWR	TSSOP	PW	16	2000	364.0	364.0	27.0
AM26C31IPWR	TSSOP	PW	16	2000	367.0	367.0	35.0
AM26C31IPWRG4	TSSOP	PW	16	2000	367.0	367.0	35.0
AM26C31QDR	SOIC	D	16	2500	367.0	367.0	38.0
AM26C31QDRG4	SOIC	D	16	2500	333.2	345.9	28.6

14 LEADS SHOWN



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. This package is hermetically sealed with a ceramic lid using glass frit.
- D. Index point is provided on cap for terminal identification only on press ceramic glass frit seal only.
- E. Falls within MIL STD 1835 GDIP1-T14, GDIP1-T16, GDIP1-T18 and GDIP1-T20.

W (R-GDFP-F16)

CERAMIC DUAL FLATPACK



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. This package can be hermetically sealed with a ceramic lid using glass frit.
- D. Index point is provided on cap for terminal identification only.
- E. Falls within MIL STD 1835 GDFP2-F16



FK (S-CQCC-N**)

LEADLESS CERAMIC CHIP CARRIER

28 TERMINAL SHOWN



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. This package can be hermetically sealed with a metal lid.
- D. Falls within JEDEC MS-004



N (R-PDIP-T**)

PLASTIC DUAL-IN-LINE PACKAGE

16 PINS SHOWN



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Falls within JEDEC MS-001, except 18 and 20 pin minimum body length (Dim A).
- The 20 pin end lead shoulder width is a vendor option, either half or full width.



D (R-PDS0-G16)

PLASTIC SMALL OUTLINE



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
- E. Reference JEDEC MS-012 variation AC.



D (R-PDSO-G16)

PLASTIC SMALL OUTLINE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



PW (R-PDSO-G16)

PLASTIC SMALL OUTLINE



- A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M—1994.
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0,15 each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0,25 each side.
- E. Falls within JEDEC MO-153



PW (R-PDSO-G16)

PLASTIC SMALL OUTLINE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



DB (R-PDSO-G**)

PLASTIC SMALL-OUTLINE

28 PINS SHOWN



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion not to exceed 0,15.

D. Falls within JEDEC MO-150

MECHANICAL DATA

NS (R-PDSO-G**)

14-PINS SHOWN

PLASTIC SMALL-OUTLINE PACKAGE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion, not to exceed 0,15.



IMPORTANT NOTICE

Texas Instruments Incorporated and its subsidiaries (TI) reserve the right to make corrections, enhancements, improvements and other changes to its semiconductor products and services per JESD46, latest issue, and to discontinue any product or service per JESD48, latest issue. Buyers should obtain the latest relevant information before placing orders and should verify that such information is current and complete. All semiconductor products (also referred to herein as "components") are sold subject to TI's terms and conditions of sale supplied at the time of order acknowledgment.

TI warrants performance of its components to the specifications applicable at the time of sale, in accordance with the warranty in TI's terms and conditions of sale of semiconductor products. Testing and other quality control techniques are used to the extent TI deems necessary to support this warranty. Except where mandated by applicable law, testing of all parameters of each component is not necessarily performed.

TI assumes no liability for applications assistance or the design of Buyers' products. Buyers are responsible for their products and applications using TI components. To minimize the risks associated with Buyers' products and applications, Buyers should provide adequate design and operating safeguards.

TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right relating to any combination, machine, or process in which TI components or services are used. Information published by TI regarding third-party products or services does not constitute a license to use such products or services or a warranty or endorsement thereof. Use of such information may require a license from a third party under the patents or other intellectual property of the third party, or a license from TI under the patents or other intellectual property of TI.

Reproduction of significant portions of TI information in TI data books or data sheets is permissible only if reproduction is without alteration and is accompanied by all associated warranties, conditions, limitations, and notices. TI is not responsible or liable for such altered documentation. Information of third parties may be subject to additional restrictions.

Resale of TI components or services with statements different from or beyond the parameters stated by TI for that component or service voids all express and any implied warranties for the associated TI component or service and is an unfair and deceptive business practice. TI is not responsible or liable for any such statements.

Buyer acknowledges and agrees that it is solely responsible for compliance with all legal, regulatory and safety-related requirements concerning its products, and any use of TI components in its applications, notwithstanding any applications-related information or support that may be provided by TI. Buyer represents and agrees that it has all the necessary expertise to create and implement safeguards which anticipate dangerous consequences of failures, monitor failures and their consequences, lessen the likelihood of failures that might cause harm and take appropriate remedial actions. Buyer will fully indemnify TI and its representatives against any damages arising out of the use of any TI components in safety-critical applications.

In some cases, TI components may be promoted specifically to facilitate safety-related applications. With such components, TI's goal is to help enable customers to design and create their own end-product solutions that meet applicable functional safety standards and requirements. Nonetheless, such components are subject to these terms.

No TI components are authorized for use in FDA Class III (or similar life-critical medical equipment) unless authorized officers of the parties have executed a special agreement specifically governing such use.

Only those TI components which TI has specifically designated as military grade or "enhanced plastic" are designed and intended for use in military/aerospace applications or environments. Buyer acknowledges and agrees that any military or aerospace use of TI components which have *not* been so designated is solely at the Buyer's risk, and that Buyer is solely responsible for compliance with all legal and regulatory requirements in connection with such use.

TI has specifically designated certain components as meeting ISO/TS16949 requirements, mainly for automotive use. In any case of use of non-designated products, TI will not be responsible for any failure to meet ISO/TS16949.

Products Applications

Audio www.ti.com/audio Automotive and Transportation www.ti.com/automotive **Amplifiers** amplifier.ti.com Communications and Telecom www.ti.com/communications **Data Converters** dataconverter.ti.com Computers and Peripherals www.ti.com/computers **DLP® Products** www.dlp.com Consumer Electronics www.ti.com/consumer-apps DSP dsp.ti.com **Energy and Lighting** www.ti.com/energy Clocks and Timers www.ti.com/clocks Industrial www.ti.com/industrial Interface interface.ti.com Medical www.ti.com/medical Logic Security www.ti.com/security logic.ti.com

Power Mgmt power.ti.com Space, Avionics and Defense www.ti.com/space-avionics-defense

Microcontrollers microcontroller.ti.com Video and Imaging www.ti.com/video

RFID www.ti-rfid.com

OMAP Applications Processors www.ti.com/omap TI E2E Community e2e.ti.com

Wireless Connectivity www.ti.com/wirelessconnectivity